

<b>Notice of References Cited</b>	Application/Control No. 10/568,653		Applicant(s)/Patent Under Reexamination ZIGER, DAVID	
	Examiner MICHAEL LAPAGE		Art Unit 2886	Page 1 of 1

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*	C	US-2002/0163649	11-2002	Hirose et al.	356/504
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	M	US-			

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#### NON-PATENT DOCUMENTS

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.